



Measurement of Differential $t\bar{t}$ Cross Section with Boosted Tops in e/μ +Jets Final State at 8 TeV Using CMS Data

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on behalf of the CMS collaboration

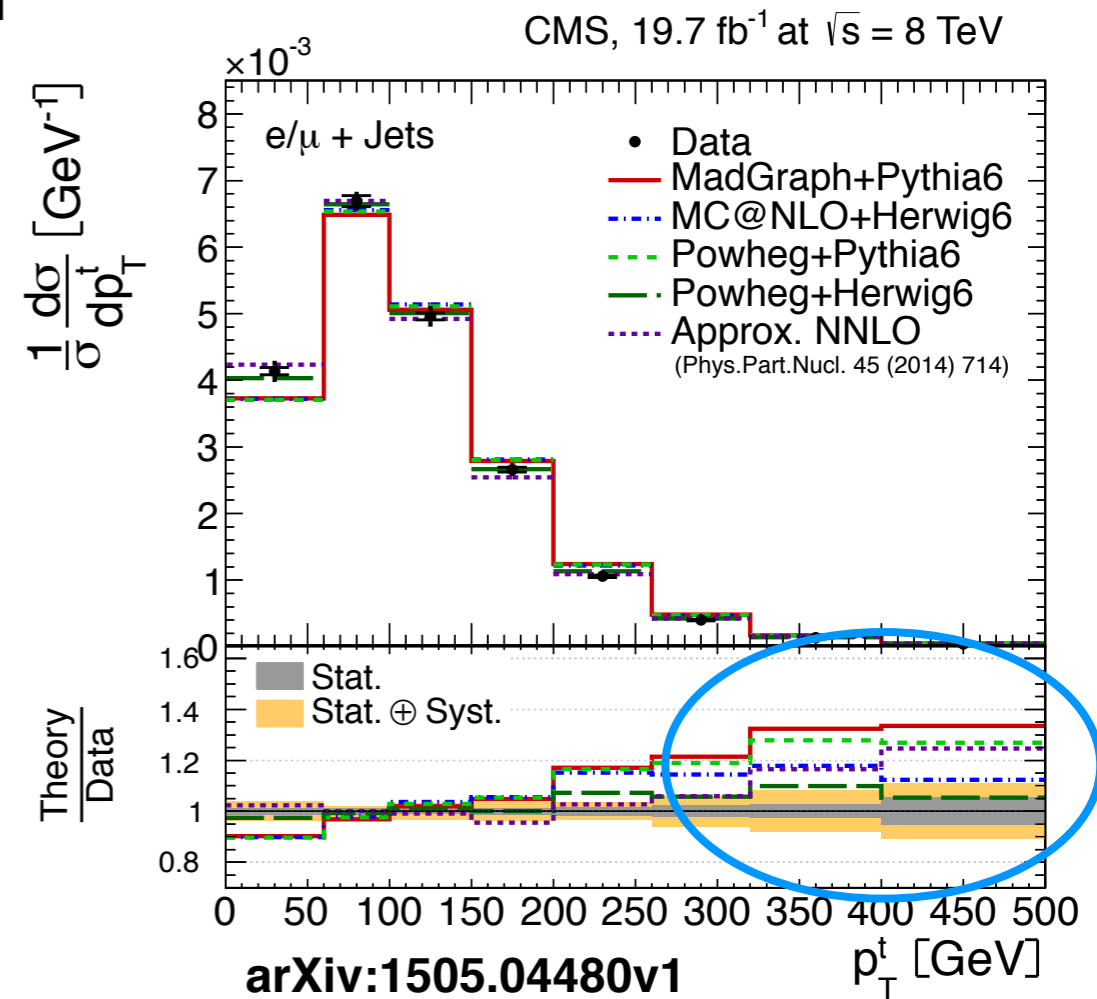
BOOST 2015, University of Chicago
12 August 2015



Introduction



- Goal: measure $t\bar{t}$ cross section at parton and particle level for $p_T(\text{top}) > 400$ GeV
 - Inclusive
 - Normalized differential
- Motivation
 - Extend measurement to higher energies
 - Important background for new physics searches
- First measurement at CMS



$p_T(\text{top})$ spectrum: MC tends to be harder than data

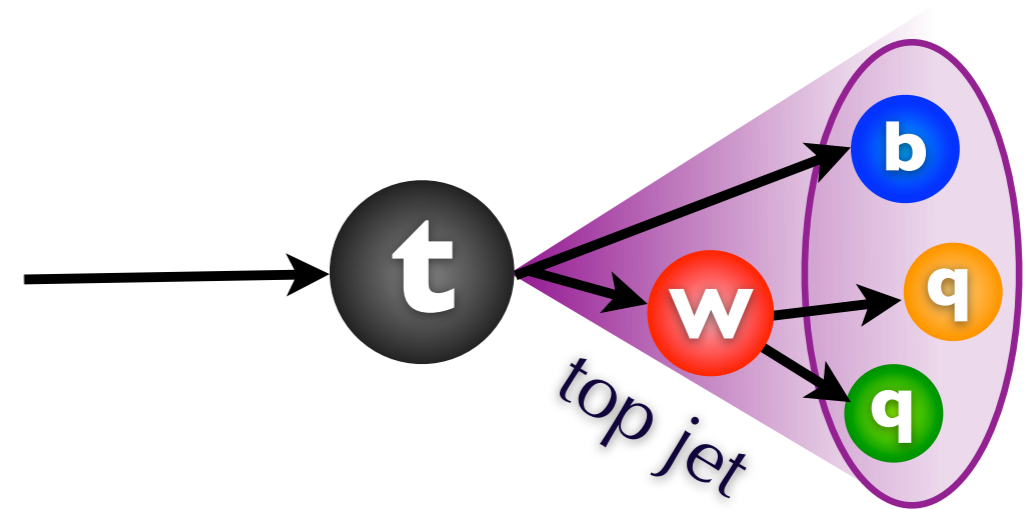
Documentation: CMS PAS TOP-14-012



Analysis Overview



- Measure $t\bar{t}$ cross section as a function of top p_T for $p_T(\text{top}) > 400$ GeV
 - Full 2012 8 TeV dataset (19.7 fb^{-1})
- e/μ +jets final state
 - Single electron or muon trigger
 - Hadronic top decay \rightarrow merged jet
- Perform fit in several kinematic regions to determine top tagging efficiency, background rates, integrated cross section
- Correct background-subtracted data distribution to normalized differential cross section at particle and parton levels



Note: leptonic top decay products not merged

Selection

Muon (electron)

- $p_T > 45$ (35) GeV
- passes 2D cut
 - $\Delta R(e/\mu, j) > 0.5$ OR $p_T^{\text{rel}}(e/\mu, j) > 25$ GeV
- electron passes triangular cut

$$|\Delta\phi(e \text{ or leading } j, E_T^{\text{miss}}) - 1.5| < 1.5 * \frac{E_T^{\text{miss}}}{75 \text{ GeV}}$$

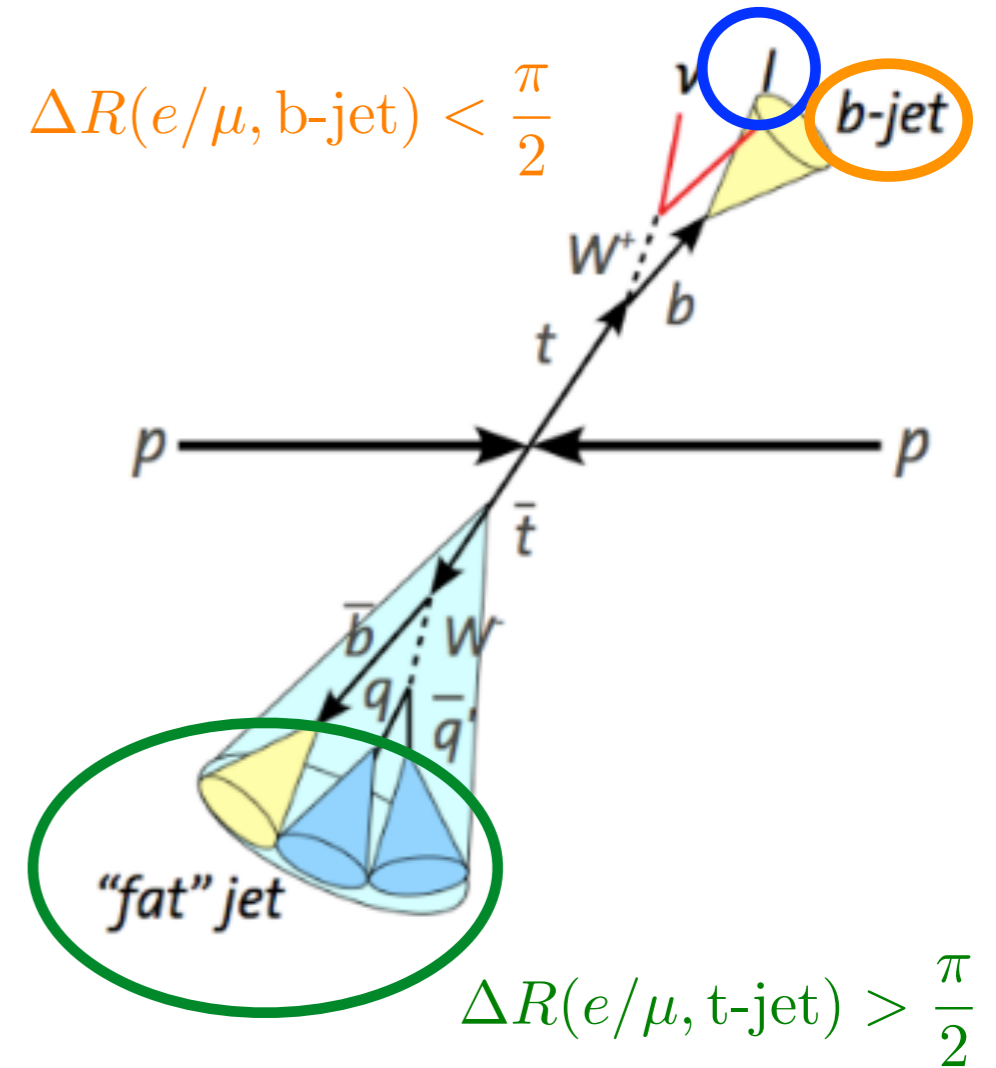
Reduce QCD

b-jet

- Anti- k_T jet, $\Delta R = 0.5$
- $p_T > 30$ GeV
- b-tagged*
 - secondary vertex mass > 0

t-jet

- Cambridge-Aachen jet, $\Delta R = 0.8$
- $p_T > 400$ GeV
- t-tagged* with CMS top tagger



*b(t)-jets without tagging requirement are 'b(t)-jet candidates'



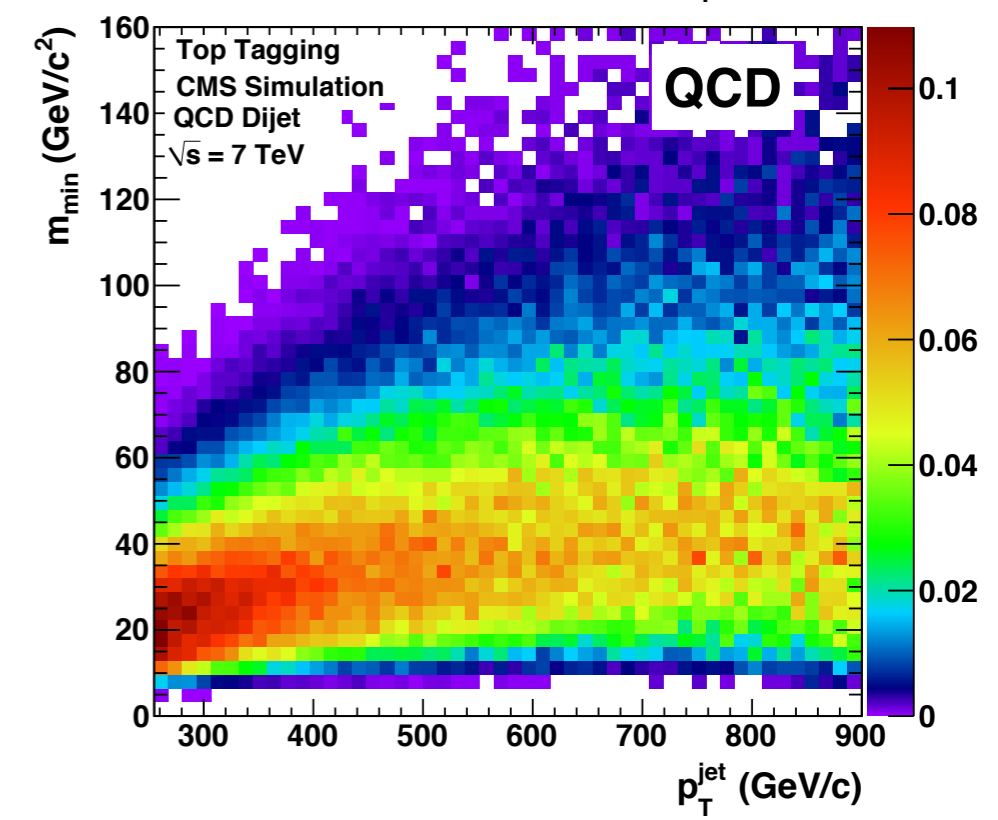
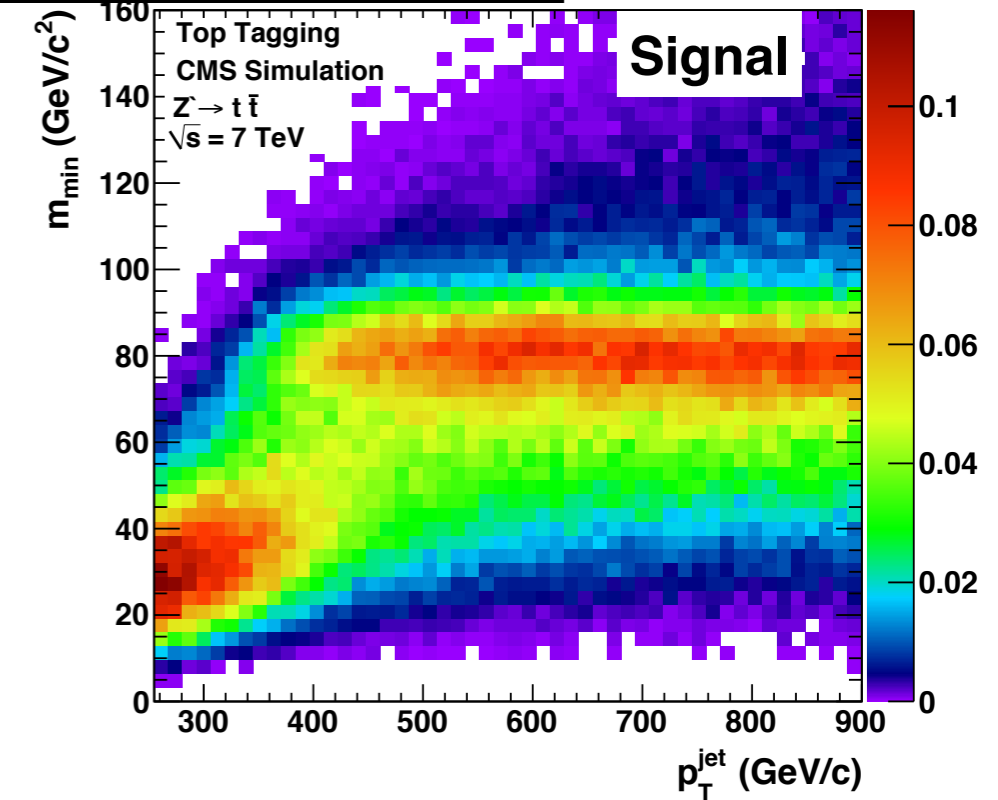
CMS Top Tagger



- Decay products of boosted top merge into single large-radius jet
 - Identify via jet substructure
- Need reasonable efficiency as low as $p_T(\text{top}) = 400$ GeV
- Use 'CMS' top tagger
 - ref. CMS-PAS-JME-13-007
- Recluster jet to identify subjets
- Require
 - ≥ 3 subjets
 - Subjet pairwise minimum mass > 50 GeV
 - $140 \text{ GeV} < \text{jet mass} < 250 \text{ GeV}$

→ 13-25% efficient,
dependent on η

CMS PAS JME-10-013

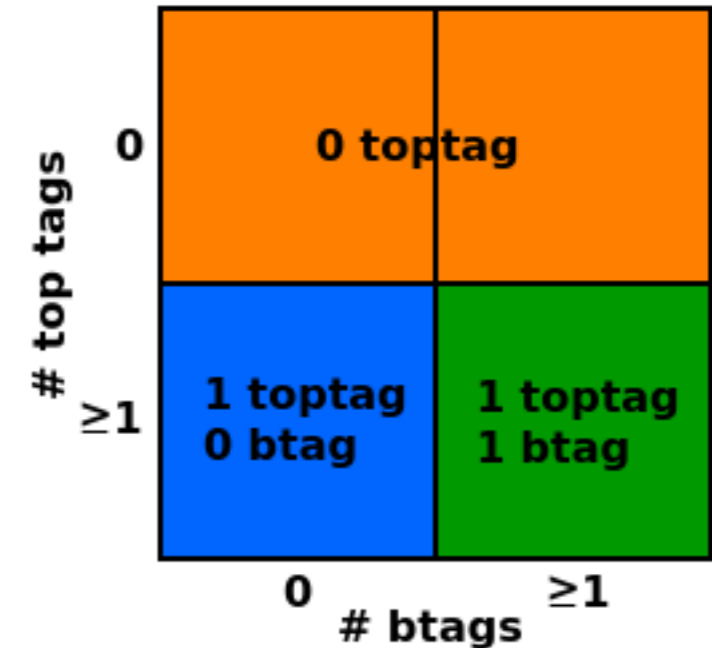




Kinematic Regions



- All events pass preselection:
 - Exactly one muon or electron
 - ≥ 1 b-jet candidate
 - ≥ 1 t-jet candidate \longrightarrow Reminder: $p_T > 400$ GeV



- Events divided into three exclusive kinematic regions:

- 0 t-tag, ≥ 0 b-tag
 - 1 t-tag 0 b-tag
 - 1 t-tag 1 b-tag
- Background dominated
- Signal dominated



Modeling



- Backgrounds: non-signal $t\bar{t}$, single top, W +Jets, QCD

- Determine rates using simultaneous fit in three kinematic regions

Fit simultaneously in μ/e channels; cross-check with separate fits

- 0 t-tag, 1 t-tag 0 b-tag: fit lepton $|\eta|$

- 1 t-tag 1 b-tag: fit secondary vertex mass of b-tagged jet

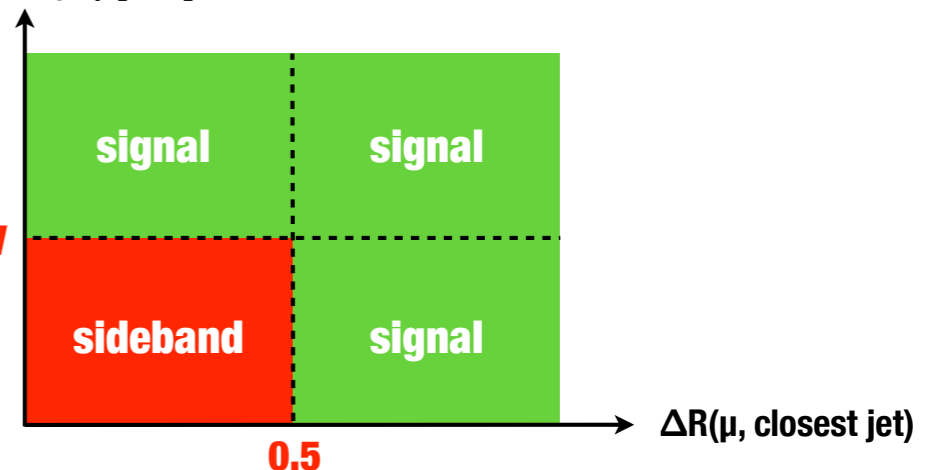
$t\bar{t}$ MC generated with POWHEG using CT10 PDF

- $t\bar{t}$, single top, W +Jets templates from MC

- QCD template from QCD-dominated data sideband (invert 2D cut on lepton)

$p_T^{\text{rel}}(\mu, \text{closest jet})$ [GeV]

25 GeV



- Also extract top tagging efficiency, integrated cross section

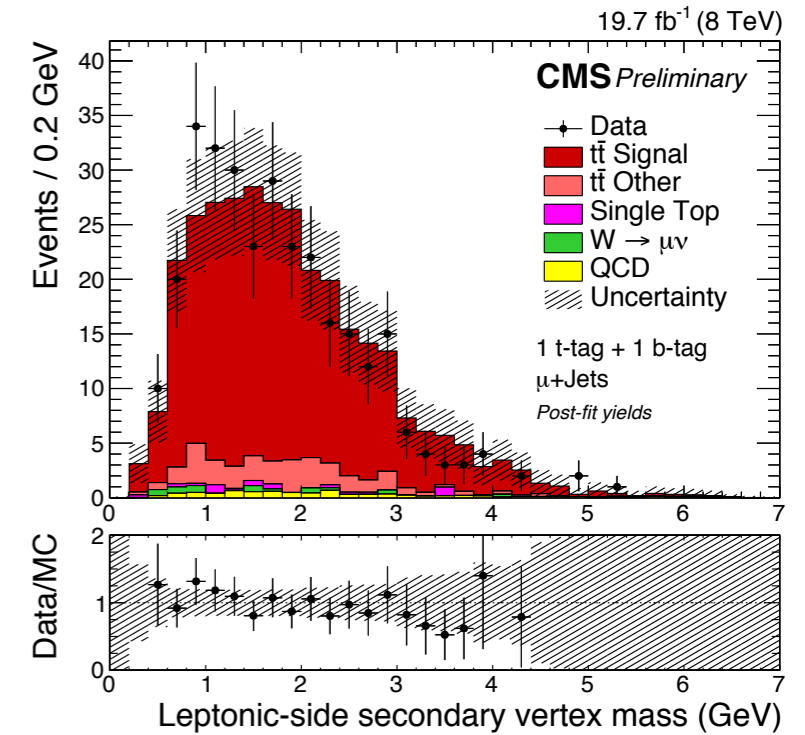
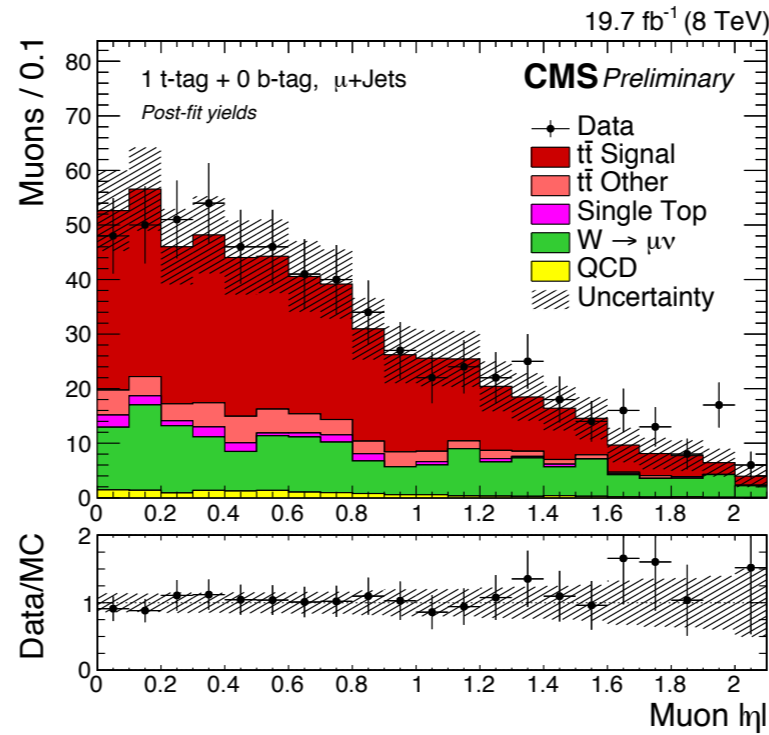
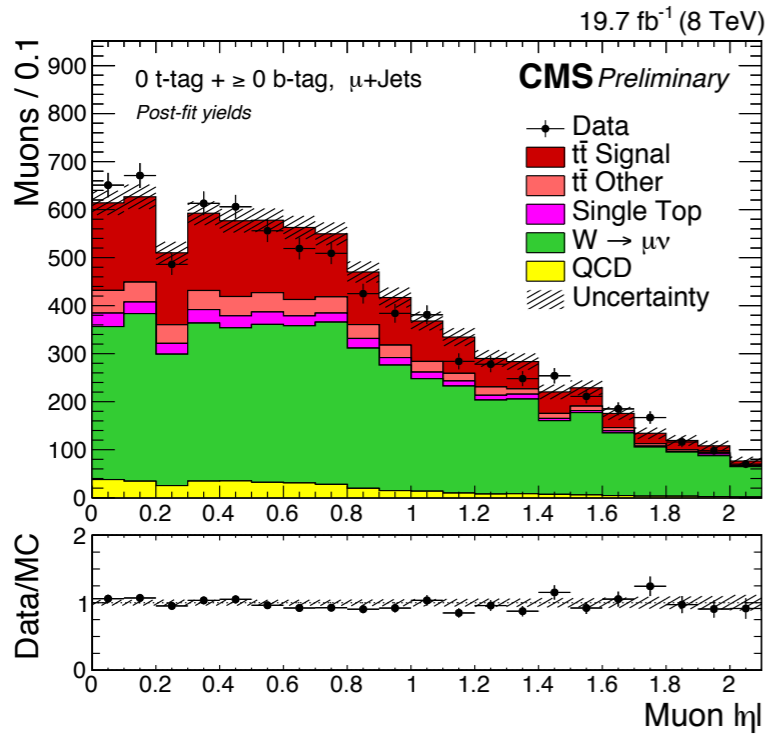


Fit Distributions

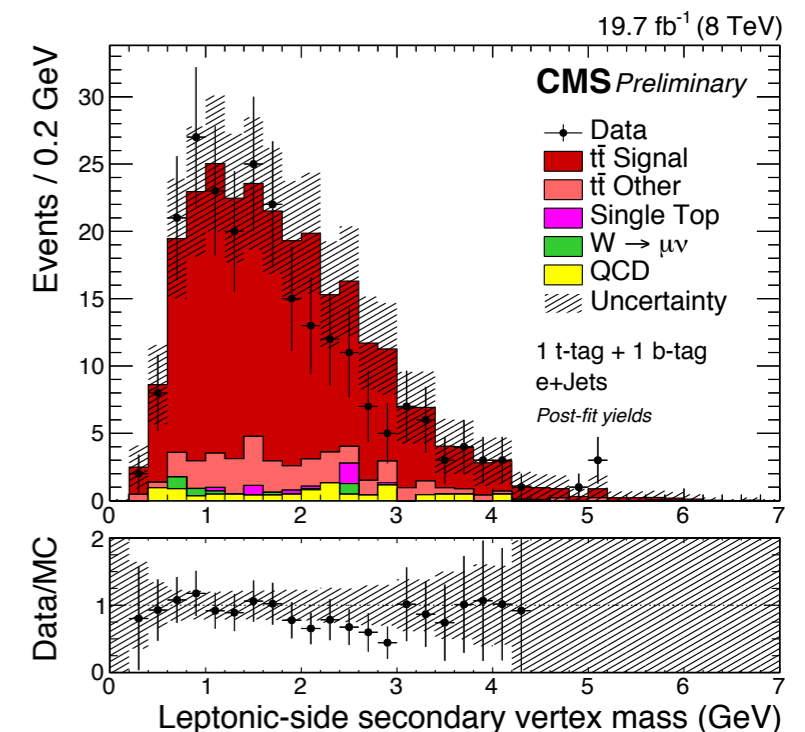
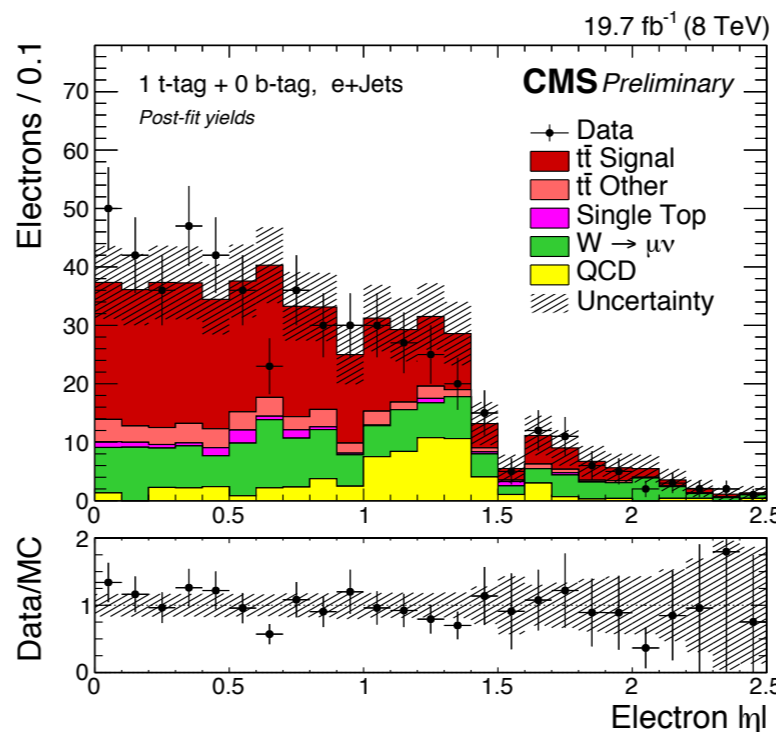
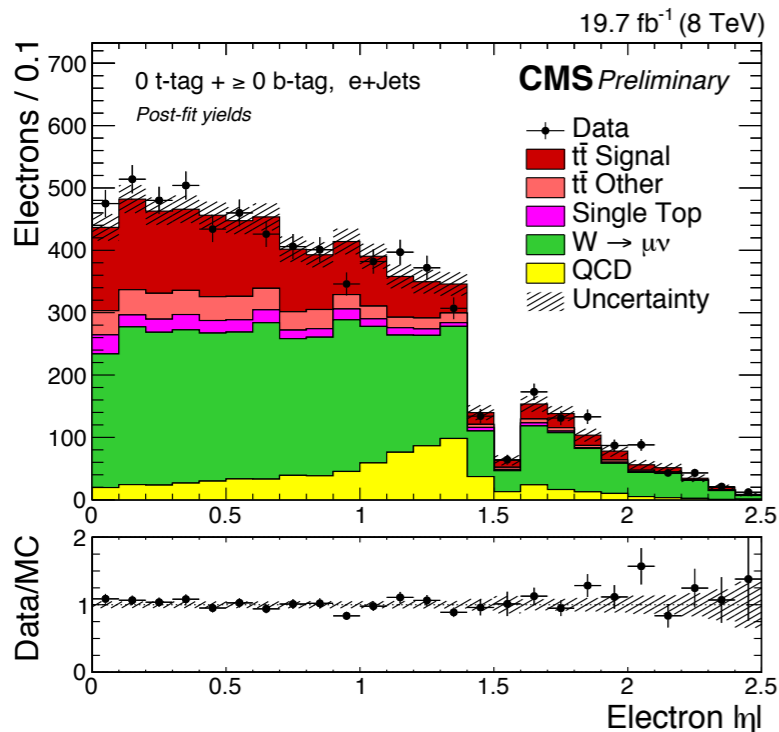


Reminder: these are kinematic distributions used in simultaneous fit

μ +jets



e +jets



0 t-tag

1 t-tag 0 b-tag

1 t-tag 1 b-tag



Systematic Uncertainties



Experimental uncertainties: nuisance parameters in fit

• Top tagging efficiency *	5%
• Background rates	
• Single top	45%
• W+Jets	7%
• QCD	15%(45%) *
• Jet Energy Scale *	1-2%
• Jet Energy Resolution *	4-7%

Constrained values from fit used in normalized differential cross section

Posterior fit uncertainties

Theoretical uncertainties

- PDF, Q^2
- Calculate separate cross sections, then compose envelope

* $e(\mu)$

* shape uncertainty

* 17% additional uncertainty on efficiency for events with $p_T(\text{top}) > 600 \text{ GeV}$

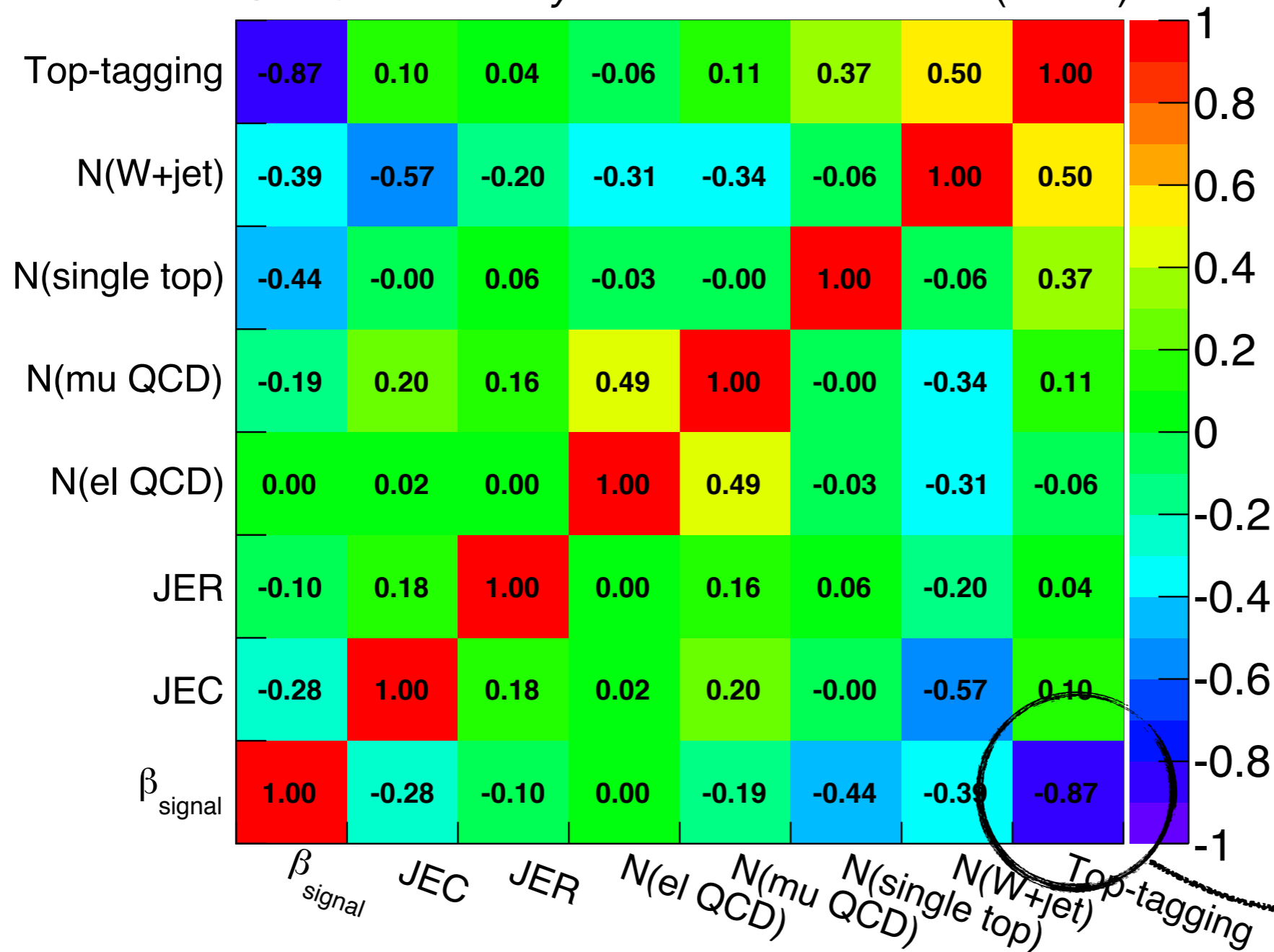


Nuisance Parameter Correlations

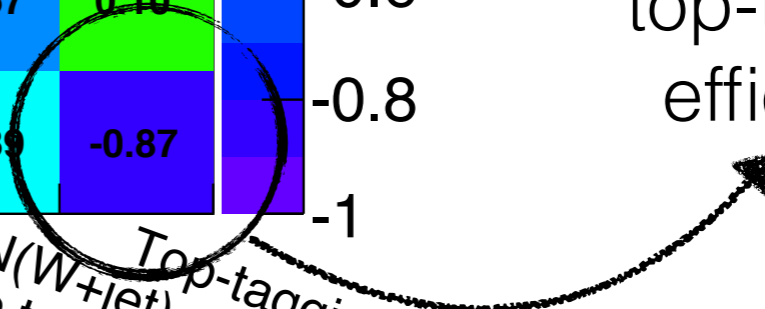


CMS Preliminary

19.7 fb⁻¹ (8 TeV)



Cross section directly depends on top-tagging efficiency





Event Counts



CMS Preliminary

Sample	Number of events (μ +jets channel)		
	0 t tag	1 t tag, 0 b tag	1 t tag, 1 b tag
$t\bar{t}$ (signal)	1923 ± 144	359 ± 27	271 ± 20
$t\bar{t}$ (non-semilep)	478 ± 36	44.7 ± 3.4	29.7 ± 2.2
Single top	294 ± 135	14.4 ± 6.6	4.1 ± 1.9
W+jets	4786 ± 327	154 ± 11	3.9 ± 0.3
QCD	358 ± 169	13.4 ± 6.3	7.6 ± 3.6
Total	7838	586	317
Data	7712	622	306

Signal normalization:
gives inclusive cross
section

Subtract normalized
backgrounds from data
to get measured

CMS Preliminary

Sample	Number of events (e+jets channel)		
	0 t tag	1 t tag, 0 b tag	1 t tag, 1 b tag
$t\bar{t}$ (signal)	1562 ± 117	289 ± 22	226 ± 17
$t\bar{t}$ (non-semilep)	458 ± 34	40.0 ± 3.0	30.1 ± 2.3
Single top	261 ± 120	11.6 ± 5.3	3.2 ± 1.5
W+jets	3667 ± 250	130 ± 8.9	2.7 ± 0.2
QCD	757 ± 128	68 ± 11	10.5 ± 1.8
Total	6704	537	273
Data	6833	538	242

Uncertainties from fit:
include all
experimental
uncertainties, no
theoretical

Use 1 t-tag 0 b-tag and
1 t-tag 1 b-tag regions
in unfolding — signal
dominated

~25% signal

55-60% signal

~85% signal

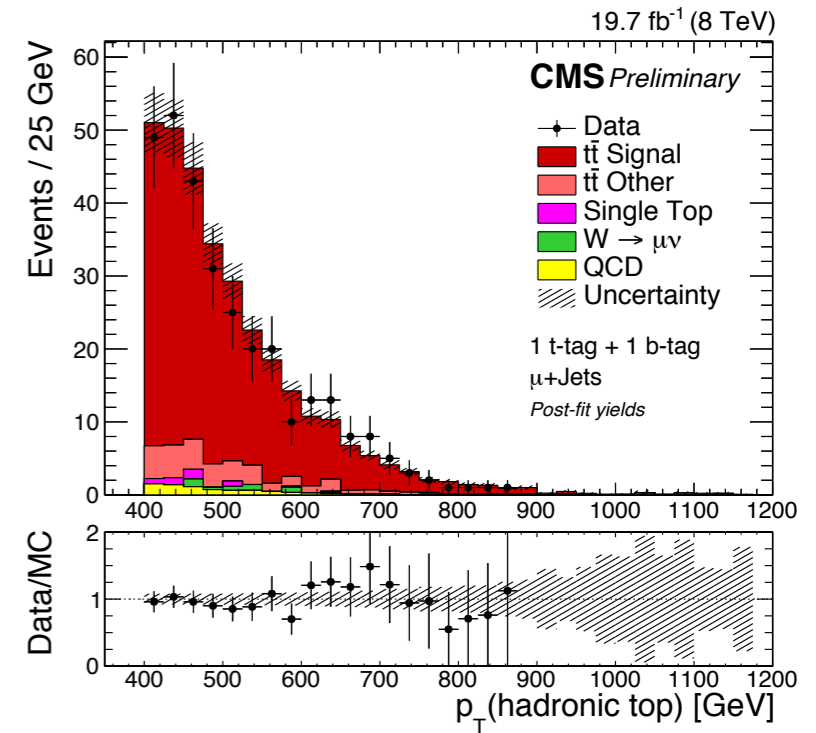
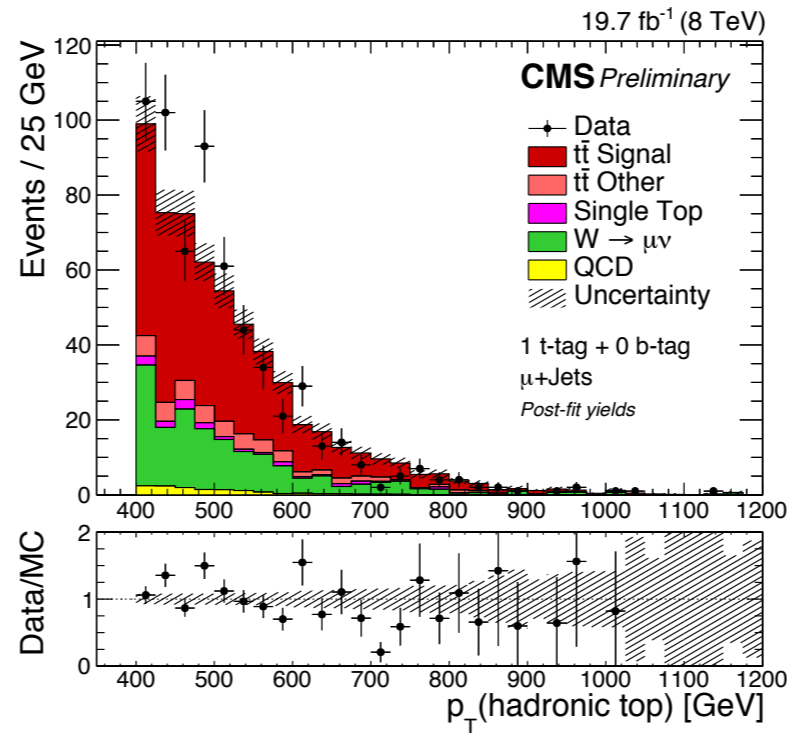
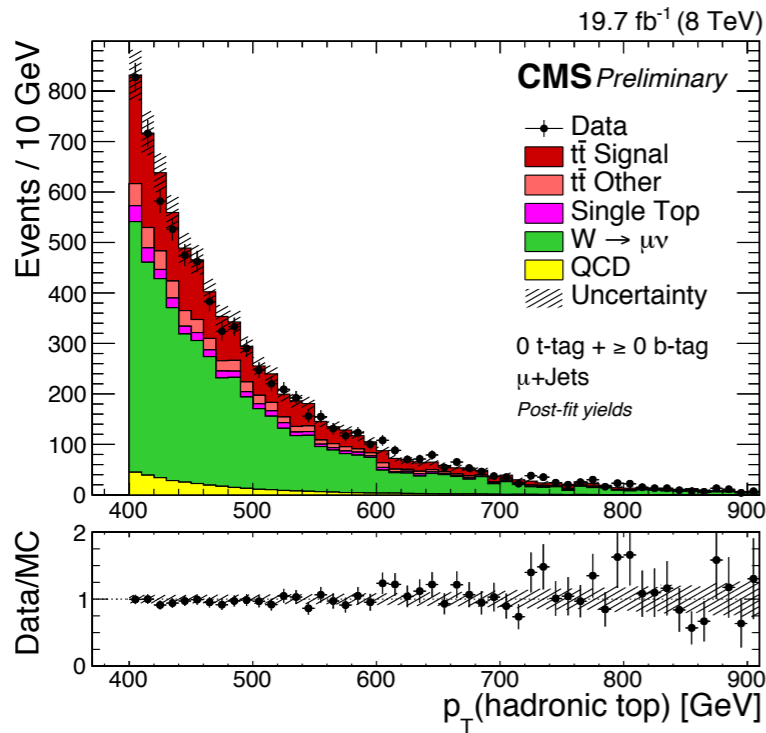


$p_T(\text{top})$ Distributions

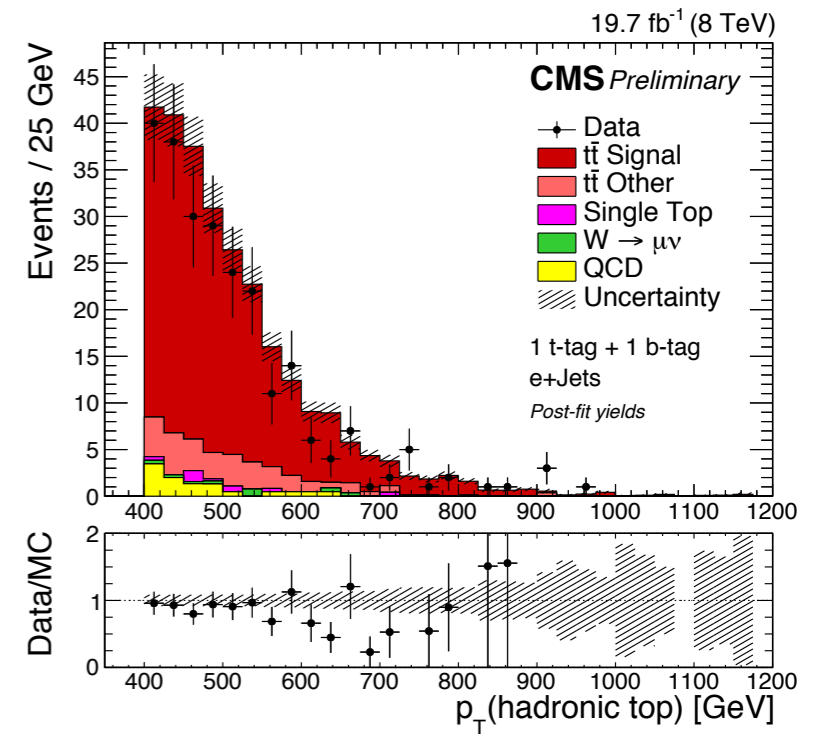
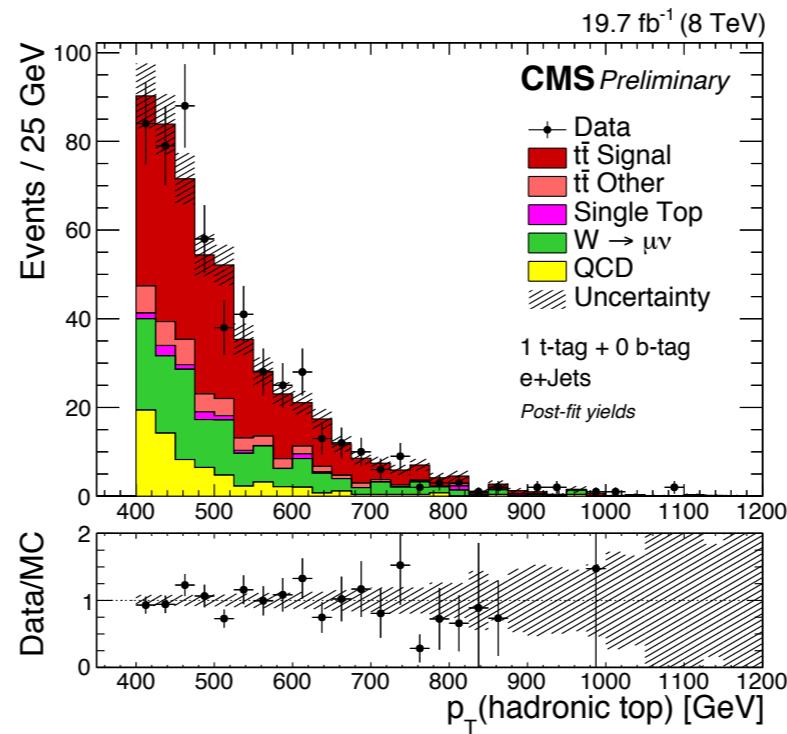
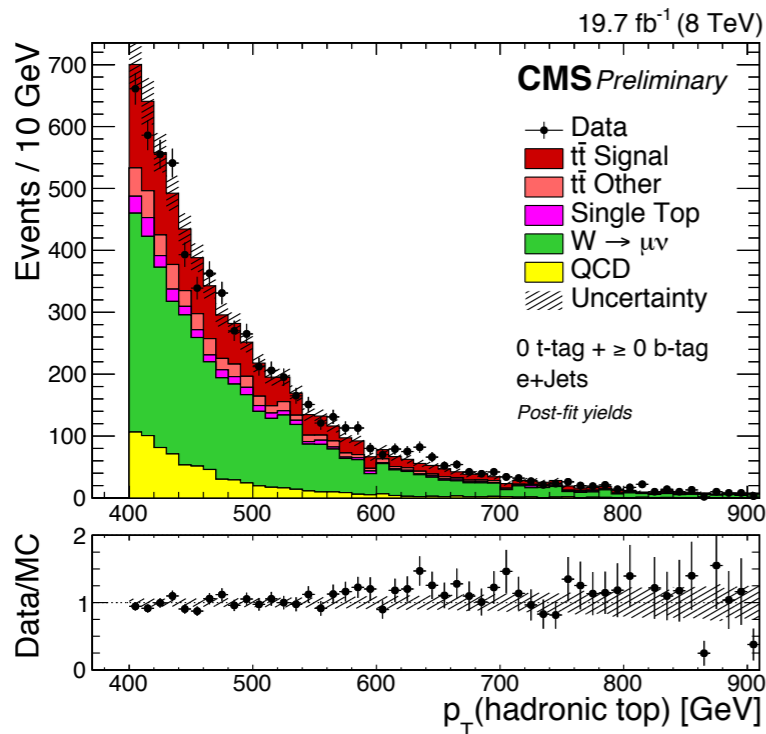


Note: $t\bar{t}$ (in red) from MC; **not** distribution used for differential cross section

μ +jets



e +jets



0 t-tag

1 t-tag 0 b-tag

1 t-tag 1 b-tag

Particle and Parton Level

Measure cross sections at particle and parton level

- Particle level

Selection:

- Matches detector-level selection
- Reduces reliance on generator

- ==1 gen-level e or μ , $p_T > 45$ GeV
- ≥ 1 gen-level b-jet
 - anti- k_T $R=0.5$ jet, $p_T > 30$ GeV,
 $0.1 < \Delta R(e/\mu, j) < \frac{\pi}{2}$
- ≥ 1 gen-level t-jet
 - C/A $R=0.8$ jet, $p_T > 400$ GeV, $\Delta R(e/\mu, j) > \frac{\pi}{2}$

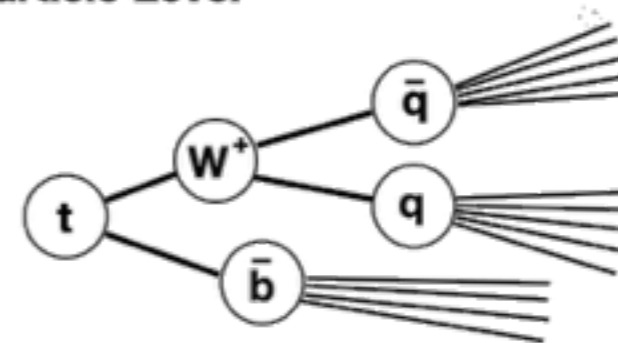
- Parton level

- Underlying event, prior to hadronization

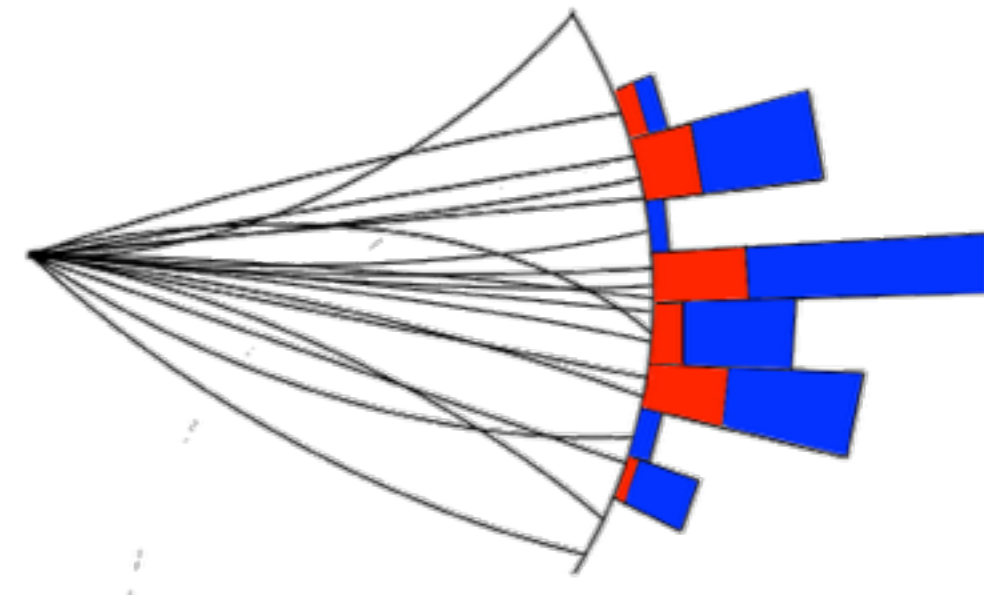
Parton Level



Particle Level



Detector Level





Inclusive Cross Section



CMS Preliminary

particle-level : $\sigma_{t\bar{t}} = 1.28 \pm 0.09$ (stat + syst) ± 0.10 (PDF) ± 0.09 (Q^2) ± 0.03 (lumi) pb

parton-level : $\sigma_{t\bar{t}} = 1.44 \pm 0.10$ (stat + syst) ± 0.13 (PDF) ± 0.15 (Q^2) ± 0.04 (lumi) pb

Powheg MC predicts $\sigma = 1.49$ pb at particle level, 1.67 pb at parton level

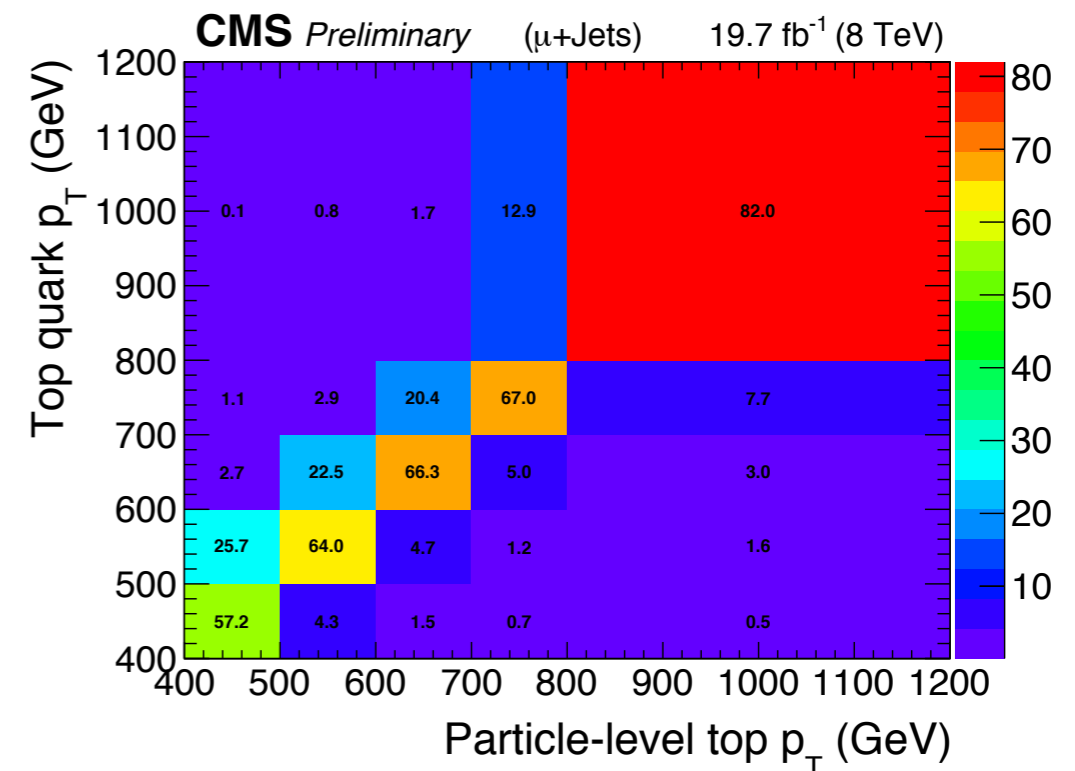
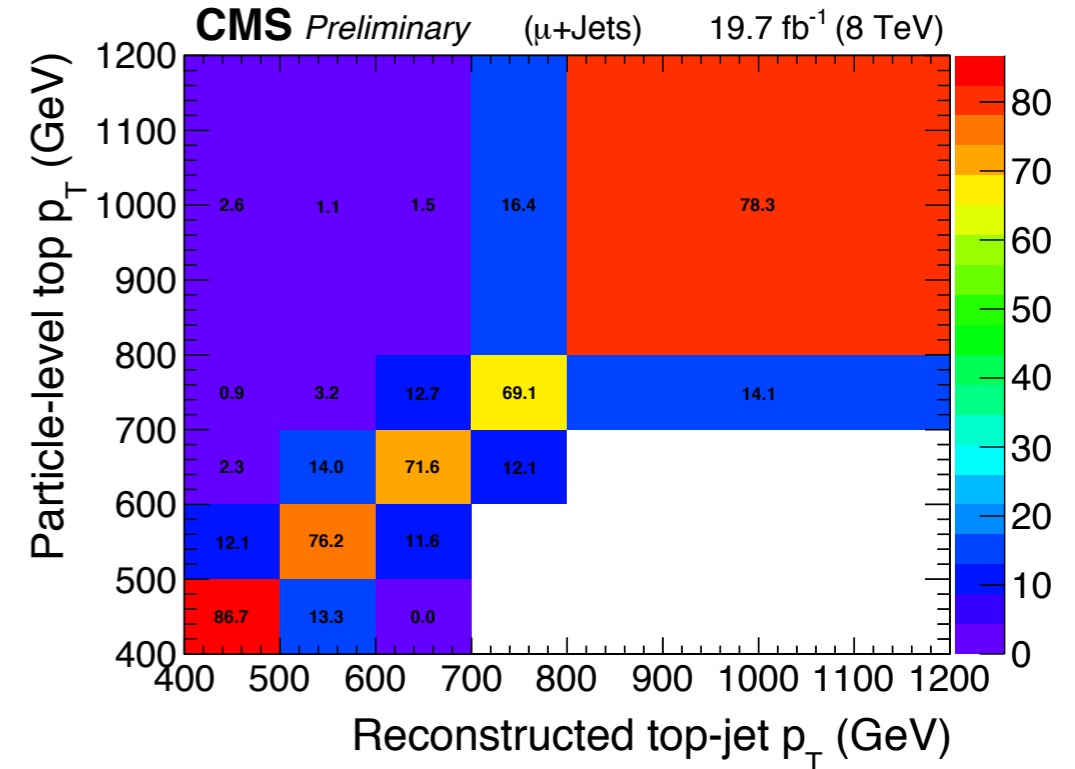
- Uncertainties:
 - Stat + sys: uncertainty from fit, includes experimental uncertainties
 - PDF / Q^2 : measure integrated cross section when varying CT10 PDF / POWHEG Q^2 within uncertainties; take envelope as uncertainty
 - Luminosity: 2.6% uncertainty



Differential Cross Section



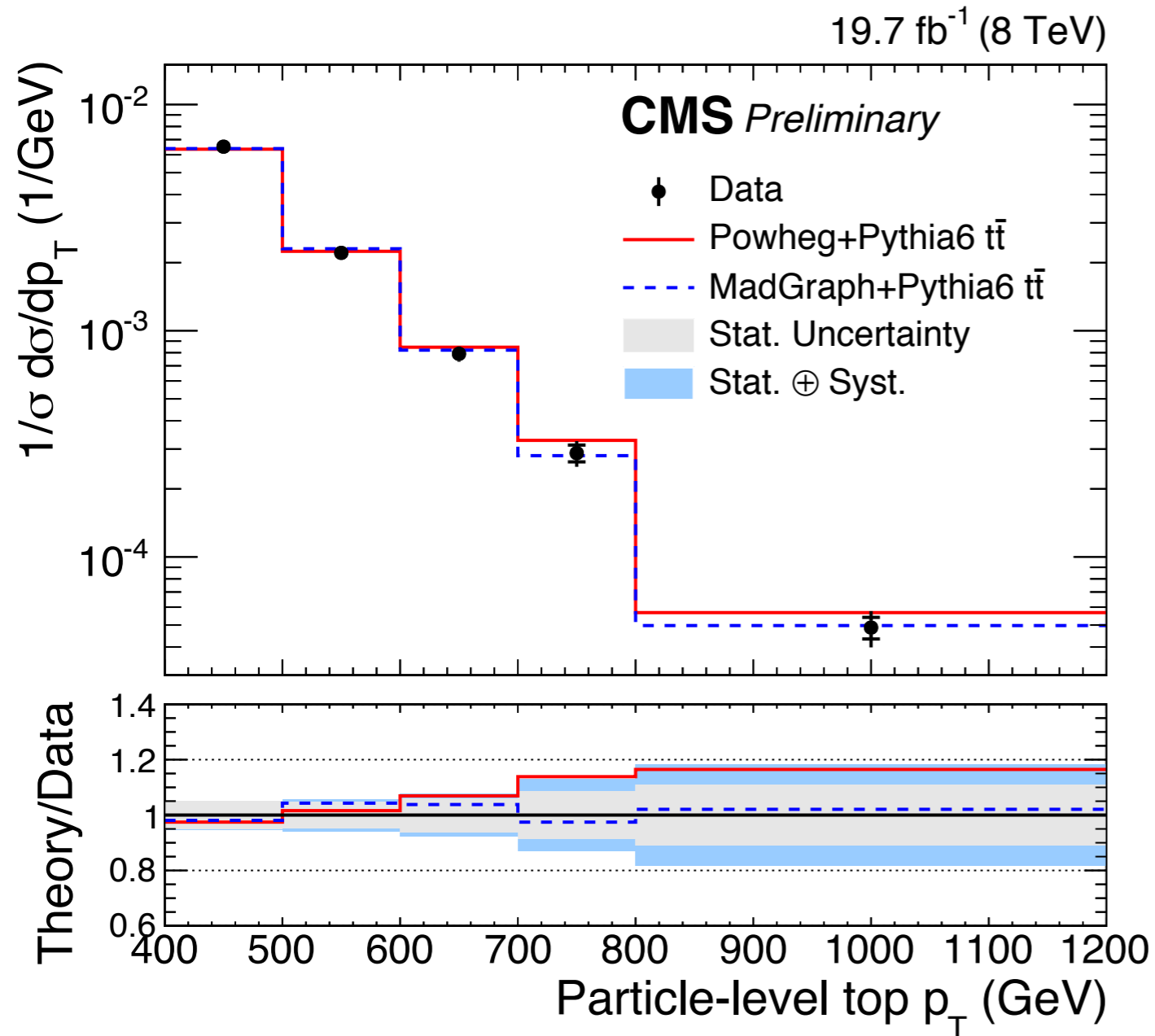
- Measure normalized differential cross section
- Start with measured $t\bar{t}$ $p_T(\text{top})$ distribution
 - Background-subtracted data, using background normalizations from fit
- Unfold to correct for detector resolution, acceptance, selection efficiency
 - 2 steps: detector-level to particle-level, particle-level to parton-level
 - Singular Value Decomposition method
 - Use both 1 t-tag 0 b-tag and 1 t-tag 1 b-tag regions
- Unfold e/ μ channels separately, then combine



Response matrices for μ channel, normalized



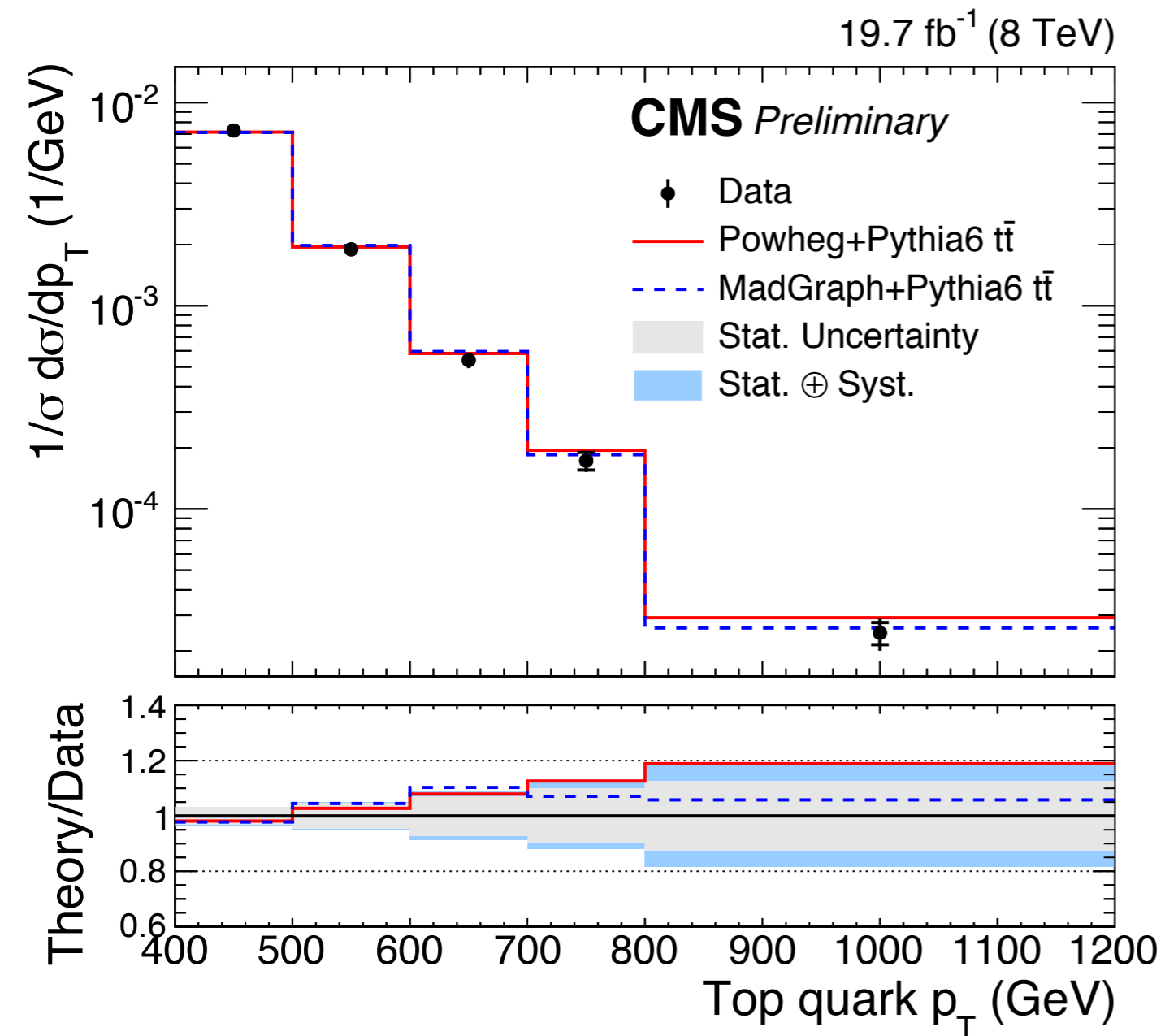
Differential Cross Section at Particle Level



- POWHEG predicts harder distribution than measured
 - Consistent with trend at lower p_T
 - 1-15% systematic uncertainty
 - Dominant contribution: Q^2
 - 5-12% statistical uncertainty



Differential Cross Section at Parton Level



- POWHEG, MadGraph predict harder distribution than measured
 - Consistent with trend at lower p_T
 - 1-13% systematic uncertainty
 - Dominant contributions: Q^2 , top-tagging efficiency
- 5-12% statistical uncertainty



Conclusions



- Measured boosted $t\bar{t}$ cross section with respect to $p_T(\text{top})$
 - First measurement at CMS
- POWHEG and MadGraph predict slightly harder $p_T(\text{top})$ distribution than data
 - Confirms trend from previous analyses
- Future plans: repeat analysis at 13 TeV
 - Greater statistics
 - Extend p_T reach of measurement

Backup



Trigger + MC Samples



- Trigger: non-isolated lepton
- Single muon: $p_{T}^{\mu} > 40$ GeV
- Electron+jets: $p_{T}^{e} > 30$ GeV + two jets with $p_{T} > 100, 25$ GeV
- MC samples

Sample	MC generator	PDF	Showering
$t\bar{t}$	POWHEG	CT10	PYTHIA6 tune Z2*
	MadGraph	CT10	PYTHIA6 tune Z2*
Single Top	POWHEG	CT10	PYTHIA6 tune Z2*
W+Jets	MadGraph	CTEQ6L1	PYTHIA6 tune Z2*

Used for cross-check



Jet Definitions



- Two standard clustering techniques used at CMS
- Regular jets: anti-kT
 - <http://arxiv.org/abs/0802.1189>
- Large-radius jets: Cambridge - Aachen
 - <http://arxiv.org/abs/hep-ph/9907280> , <http://arxiv.org/abs/hep-ph/9707323>



Nuisance Parameter Uncertainties



Uncertainties on nuisance parameters prior to performing fit

Parameter	Constraint	Type
Top-tagging efficiency	$\pm 25\%$	Rate and shape
Jet energy scale	$\pm 1\sigma_{\text{jec}} (\sim 1 - 4\%)$	Rate and shape
Jet energy resolution	$\pm 1\sigma_{\text{jer}} (\sim 5 - 10\%)$	Rate and shape
QCD normalization	$\pm 100\%$	Rate only
W+jets normalization	$\pm 50\%$	Rate only
Single top normalization	$\pm 50\%$	Rate only
Non-semileptonic $t\bar{t}$ normalization	$\pm 50\%$	Rate only

JER/JEC: a priori uncertainties from CMS JME group (arXiv:1107.4277)